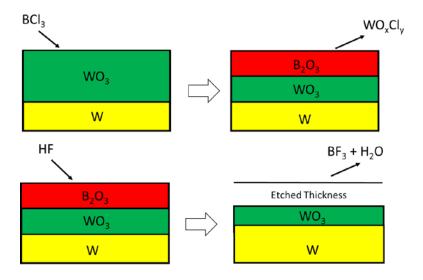
## WO₃ and W Thermal Atomic Layer Etching Using "Conversion-Fluorination" and "Oxidation-Conversion-Fluorination" Etching Mechanisms

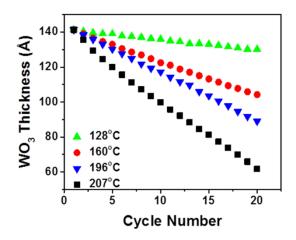
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**Figure S1.** "Conversion-fluorination" etching mechanism where the  $WO_3$  surface is first converted to a  $B_2O_3$  layer and then the  $B_2O_3$  layer is etched by forming volatile  $BF_3$  and  $H_2O$ .



**Figure S2.** WO<sub>3</sub> thickness versus cycle number during WO<sub>3</sub> ALE using BCl<sub>3</sub> and HF as the reactants for different temperatures. The WO<sub>3</sub> ALE etch rates increase with temperature from 0.55 Å/cycle at 128°C to 4.19 Å/cycle at 207°C.